



## **NanoScan Ltd joins forces with ION-TOF GmbH**

Dübendorf, March 2009

Ion-TOF GmbH, a leading European manufacturer of instrumentation for surface analysis, and NanoScan Ltd have decided to join forces in the development and the marketing of their high-tech instruments. For this purpose, ION-TOF GmbH has recently acquired the majority of the shares of NanoScan Ltd.

ION-TOF is known for its innovative ion beam technology for surface analysis with various product lines in Time-of-Flight Secondary Ion Mass Spectrometry (TOF-SIMS) and Low Energy Ion Scattering (LEIS). Founded in 1989 as a classical spin-off of the University of Münster, ION-TOF has meanwhile become the technological leader in these areas, with more than 190 instruments in operation worldwide.

After the acquisition NanoScan will remain an independent company in Switzerland. Dr. Raphaëlle Dianoux has been appointed CEO and will lead the company together with Dr. Guido Tarrach as CTO. Both scientists have long-term experience in the development and the application of scanning probe microscopy. Under their leadership NanoScan will continue to develop, sell and service the high-resolution magnetic force microscope (hr-MFM) and the high-resolution atomic force microscope for the physical properties measurement system (PPMS<sup>®</sup>-AFM).

For more information, contact:

Dr. Raphaëlle Dianoux  
NanoScan Ltd  
Ueberlandstrasse 129  
8600 Duebendorf  
Switzerland

Tel: +41 43 931 0240

Email: [r.dianoux@nanoscan.ch](mailto:r.dianoux@nanoscan.ch)

Web: [www.nanoscan.ch](http://www.nanoscan.ch)